

<b>Notice of References Cited</b>	Application/Control No. 10/665,440	Applicant(s)/Patent Under Reexamination SKINLO, DAVID M.	
	Examiner Dah-Wei D. Yuan	Art Unit 1745	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,114,059	09-2000	Watanabe et al.	429/120
*	B	US-6,387,561	05-2002	Nemoto et al.	429/51
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

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